CORNING

Tropel[®] UltraSort II

A fully automated wafer flatness metrology platform with customizable measurement components

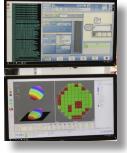
The UltraSort II is a flexible, high-throughput, fully automated platform that incorporates any Tropel wafer flatness measurement system, providing full surface bow, warp, TTV, and stepper simulation parameters as described in SEMI M1. The UltraSort II can also accept additional modules including additional cassettes, another interferometer, OCR, ROA, and many more. The system modularity allows you to get more value out of your automated wafer flatness inspection system. The UltraSort II platform is designed to enable full factory automation including SECS/GEM, GEM 300 host systems, along with other custom data export systems.



Key Specifications	Available Wafer Configurations
CE Compliance	2"-6" Open Cassettes
Semi S2/S8 Compliance	4"-8" Open Cassettes
ISO 9001:2015, 9014:2015, 14001	300mm FOUP

Throughput

FlatMaster clamped/unclamped	150 wph
FlatMaster clamped/unclamped/thickness	120 wph
FlatMaster MSP clamped/unclamped/thickness	60 wph





For more information about the UltraSort II or any other of our Tropel® Metrology Instruments, please contact: Corning Tropel Corporation 60 O'Connor Road Fairport, New York 14450

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